

# PORTABLE SURFACE ROUGHNESS TESTER SURFTEST SJ-410 SERIES

Numerous options provide easier, smoother and more accurate measurements





# Portable surface roughness tester evolves!

The large touch-screen, color-graphic LCD ensures both intuitive control and advanced operability

# Enhanced power for making measurements on site

#### Color-graphic LCD

The color-graphic LCD with excellent visibility displays calculated results and assessed profiles even clearer. This is useful for checking results without printing them out.

## **Backlight provided**

A backlight improves usability in dim testing environments.

# **Applicable standards**

#### Complies with many industry standards

The Surftest SJ-410 complies with the following standards: JIS (JIS-B0601-2001, JIS-B0601-1994, JIS B0601-1982), VDA, ISO-1997, and ANSI.

Standar d

# Touch screen for easier operations

The screen display can be switched between icon display and text display.





Icon display

Text display

#### Easy to use and highly functional

This portable surface roughness tester is equipped with analysis functionality rivaling that of benchtop surface roughness testers.



Simple contour analysis function



# **Multilingual support**

The display interface supports 16 languages.



## High accuracy measuring

#### A wide range, high-resolution detector

Measuring range/ resolution 800µm/0.01µm 80um/0.001um

8µm/0.0001µm

## **High straightness** drive unit

Straightness/ traverse length 0.3µm/25mm (**SJ-411**) 0.5µm/50mm (SJ-412)



# Surftest SJ-410

## Interfaces

## A variety of interfaces supplied as standard

The external device interfaces that come as standard include USB, RS-232C, SPC output and footswitch I/F.



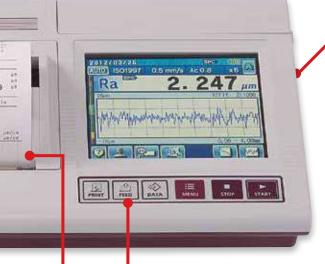
## Data storage

## Memory card (optional) is supported

The measurement conditions and data can be stored in a memory card (optional) and recalled as required. This enables batch analysis and printout of data after on-site measurement.



- •Measurement condition
- Internal memory: 10 sets Memory card: 500 sets
- •Measurement result Memory card: 1000 sets



## **Password protection**

#### Access to functions can be restricted by a password

A pre-registered password can limit use of measurement conditions and other settings to the tester's administrator.





## **Key-sheet buttons**

A sturdy key-sheet-button panel with superior durability in any environment is provided. For repeat measurement of the same work, simply pressing the start switch can complete measurement, analysis and printout.

## Carrying case

The unit is easily transported in a dedicated carrying case which includes holders for the accessories as well as the tester itself. (Standard accessory.)



#### **Printer**

# High-speed printer prints out measurement results on site

A high-quality, high-speed thermal printer prints out measurement results. It can also print a BAC curve or an ADC curve as well as calculated results and assessed profiles. These results and profiles are printed out in landscape format, just as they appear on the color-graphic LCD.





# **Enhanced measuring functions**

## Your choice of skidless or skidded measurement

Patent registered in Japan, U.S.A.. Patent pending in Germany

#### Skidless measurement

Skidless measurement is where surface features are measured relative to the drive unit reference surface. This measures waviness and finely stepped features accurately, in addition to surface roughnness, but range is limited to the stylus travel available. The SJ-410 series supports a variety of surface feature measurements simply by replacing the stylus.

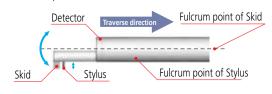


Measuring example of stepped Measured profile features: Skidless



#### Skidded measurement

In skidded measurements, surface features are measured with reference to a skid following close behind the stylus. This cannot measure waviness and stepped features exactly but the range of movement within which measurement can be made is greater because the skid tracks the workpiece surface contour.



Measuring example of stepped features: Skidded



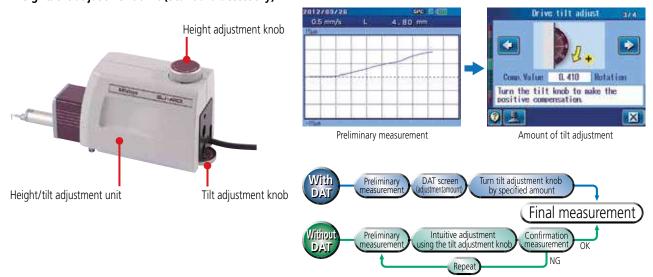


# Powerful support for leveling

Patent registered in Japan, U.S.A.. Patent pending in Germany

The height/tilt adjustment unit comes as standard for leveling the drive unit prior to making skidless measurements and, supported by guidance from the unique D.A.T. function, makes it easy to achieve highly accurate alignment.

#### Height/tilt adjustment unit (Standard accessory)

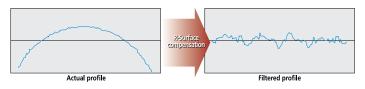


When the SJ-410 Series detector is mounted on the manual column stand\*<sup>1</sup> for measurement, it can be combined with any of the optional products for easier leveling: leveling table\*<sup>1</sup>, 3-axis alignment table\*<sup>1</sup> or tilt adjustment unit\*<sup>1</sup>.

<sup>\*1:</sup> For details about optional products, see Pages 6-7.

# More measuring functions than expected from a compact tester

Usually, a spherical or cylindrical surface (R-surface) cannot be evaluated, but, by removing the radius with a filter, R-surface data is processed as if taken from a flat surface.





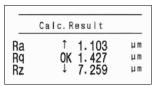
## Recalculating

Previously measured data can be recalculated for use in other evaluations by changing the current standard, assessed profile and roughness parameters.

# **GO/NG** judgement function

An "OK/NG" judgment symbol is displayed when limits are set for the roughness parameter. In case of "NG," the calculated result is highlighted. The calculated result can also be printed out.



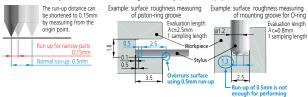


The "OK" symbol means the measurement is within the limits set; "NG" means it is not, in which case an arrow points to either the upper or lower limit in the printout.

# Narrow space measuring function Patent pending in Japan

Surface roughness measurement requires a run-up distance before starting the measurement (or retrieving data). When the SJ-410 Series measures, its run-up distance is normally set to 0.5mm. This distance, however, can be shortened to 0.15mm using the narrow part measurement function (starting from the origin point of the drive unit). The function extends the possibility of measurement of narrow locations such as grooves in piston ring / O-ring mounts.

#### Narrow space measuring Typical applications



# Real sampling

This function samples stylus displacement for a specified time without engaging detector traverse, which enables use as a simplified vibration meter or displacement gage incorporated in another system.

#### Assessing a single measurement result under two different evaluation conditions

A single measurement enables simultaneous analysis under two different evaluation conditions. A single measurement allows calculation of parameters and analysis of assessed profiles without the need for recalculation after saving data, contributing to higher work efficiency.





#### Arbitrary sampling length setting

This function allows a sampling length to be arbitrarily set in 0.01mm increments (SJ-411: 0.1mm to 25mm, SJ-412: 0.1mm to 50mm). It also allows the **SJ-410** series to make both narrow and wide range measurements.

# Simple contour analysis function

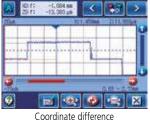
Point group data collected for surface roughness evaluation is used to perform simplified contour analysis (step, step height, area and coordinate variation). It assesses minute forms that cannot be assessed by a contour measurer.







Dimensions



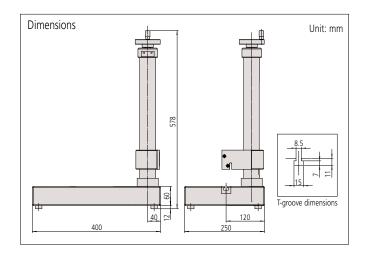


# **Optional Accessories**

# Simple column stand

Can be adjusted to match the height of the item to be measured.





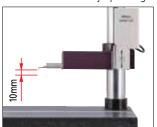
# Options for simple column stand

Three new optional products are available to be attached to the manual column stand (**No.178-039**). You can choose the unit that suits your application. Or, you can also use the three products in any combination. Using the optional units makes **SJ-411/412** more convenient and easier to use to ensure accurate measurements.

#### Auto-set unit (178-010)\*

This unit enables the vertical (Z axis) direction to be positioned automatically (auto-set function).

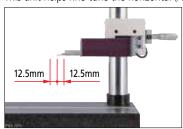
A single button operation completes a series of operations from measurement, saving and auto-return (saving and auto-return can be switched on and off by operating the drive unit).





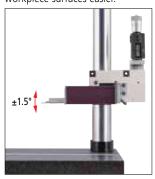
#### X-axis adjustment unit (178-020)\*

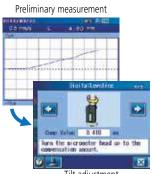
This unit helps fine-tune the horizontal (X axis) direction.



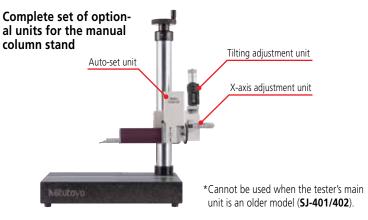
#### Tilting adjustment unit (178-030)\*

This unit is used for aligning the workpiece surface with the detector reference plane. It supports the DAT function to make the leveling of workpiece surfaces easier.





Tilt adjustment



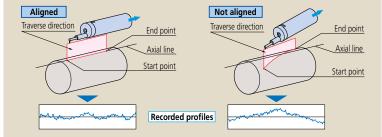
# 3-axis Adjustment Table: 178-047

Patent registered in Japan, U.S.A.. Patent pending in Germany

This table helps make the alignment adjustments required when measuring cylindrical surfaces. The corrections for the pitch angle and the swivel angle are determined from a preliminary measurement and the Digimatic micrometers are adjusted accordingly. A flat-surfaced workpiece can also be leveled with this table.



\*V-block not included



# DAT Function for the optional leveling table

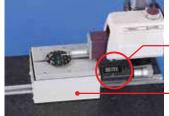
Patent registered in Japan, U.S.A.. Patent pending in Germany

The levelling table can be used to align the surface to be tested with the detector reference plane. The operator is guided through the procedure by screen prompts.



No.178-048

Inclination adjustment angle: ±1.5° Table dimensions: 130×100mm Maximum load: 15kg



DAT screen guides the user when leveling Digimatic micrometer

Amount of micrometer head adjustment required

Leveling table (DAT) (Option)

178-049

Movement is in X- and Y-axes only.

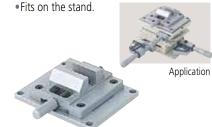


# XY leveling tables

The tester includes X- and Y-axes micrometer heads. This makes axis alignment much easier because the tilt adjustment center is the same as the rotation center of the table. (Code No.178-042-1/178-043-1)



#### **Precision vise**



Order No.	178-019
Clamping method	Sliding jaws
Jaw opening	36mm
Jaw width	44mm
Jaw depth	16mm
Height	38mm

#### Cylinder attachment

This block can be positioned on top of cylindrical objects to perform measurements.

#### No.12AAB358

Diameter: ø15~60mm

#### Configuration:

- •Cylindrical measurement block
- Auxiliary block
- \*Drive unit not included. Clamp



# Reference step specimen

Used to calibrate detector sensitivity.

#### No.178-611

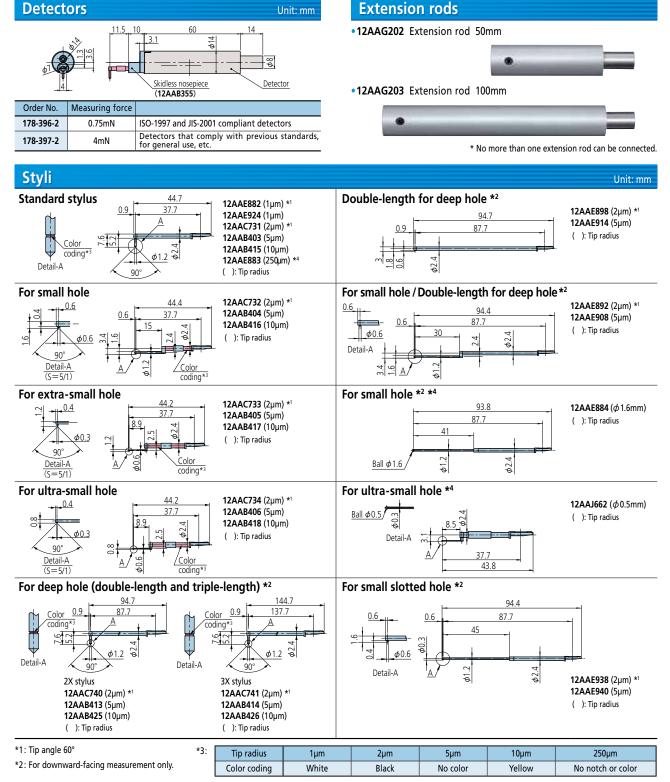
Step nominal values: 2µm/10µm

Unit: mm

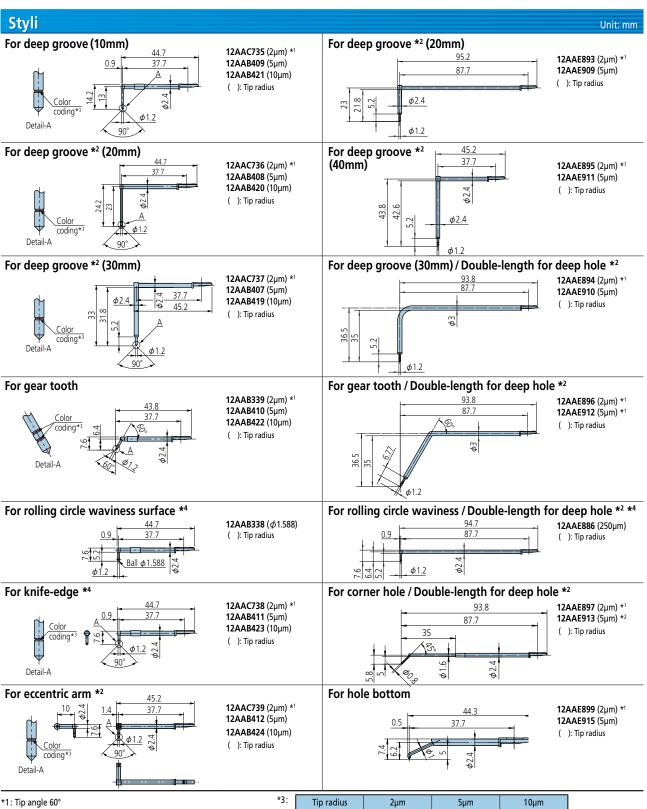




# **Optional Accessories: Detectors / Styli**



<sup>\*4:</sup> Used for calibration, a standard step gauge (No.178-611, option) is also required



<sup>\*2:</sup> For downward-facing measurement only.

<sup>\*</sup>Customized special interchageable styli are available on request, Please contact any Mitutoyo office for more information.

Color coding Black No color Yellow

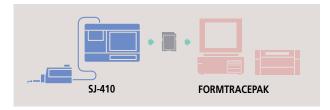
<sup>\*4:</sup> Used for calibration, a standard step gauge (No.178-611, option) is also required



# **Optional Accessories: For External Output**

# Contour / Roughness analysis software FORMTRACEPAK

More advanced analysis can be performed by loading SJ-410 series measurement data to software program FORMTRACEPAK via a memory card (option) for processing back at base.



# Digimatic mini processor DP-1VR

By connecting this printer to the Surftest SJ-410's digimatic output, you can print calculation results, perform a variety of statistical analyses, draw a histogram or D chart, and also perform complicated operations for X-R control charts.



No.264-504 -5A

 $SJ-410 \rightarrow DP-1VR$  Connecting cable

1m: No.936937 2m: No.965014

# Measurement Data Wireless Communication System U-WAVE

This unit allows you to remotely load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.



**U-WAVE-R** (Connects to the PC) No.02AZD810D



U-WAVE-T \* (Connects to the SJ-410) No.02AZD880D

\*Requires the optional Surftest SJ-410 connection cable.

No.02AZD790D

# Simplified communication program for **SURFTEST SJ series**

The Surftest SJ-410 series has a USB interface, enabling data to be transferred to a spreadsheet or other software.

We also provide a program that lets you create inspection record tables using a Microsoft Excel\* macro.

This program can be downloaded free of charge from the Mitutoyo website. http://www.mitutoyo.com/about/contacting-mac/ surftest-simple-communication-program/



#### Required environment\*

 OS: Windows XP-SP3 • Spreadsheet software: Microsoft Excel 2002 Microsoft Excel 2003 Windows Vista Microsoft Excel 2007 Windows 7 Microsoft Excel 2010/13 Windows 8 (32/64bit)

\*Windows OS and Microsoft Excel are products of Microsoft Corporation. \*PC OS must be 32-Bits

#### The optional USB cable is also required.

• USB cable for SJ-410 series No.12AAD510

# Calculation results input unit INPUT TOOL

This unit allows you to load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC via a USB connector. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.



**USB-ITN-D** No.06ADV380D



USB keyboard signal conversion type\* IT-012U No.264-012-10

\*Requires the optional Surftest SJ-410 connection cable

1m: No.936937 2m: No.965014

# Optional accessories, consumables, and others for SJ-410

Printer paper (5 rolls) No.270732 Durable printer paper (5 rolls) No.12AAA876 Touch-screen protector sheet (10 sheets) No.12AAN040 Memory card (2GB) \* No.12AAL069 Connecting cable (for RS-232C) No.12AAA882

\*micro SD card (with a conversion adapter to SD card)

# **Specifications**

Measuring Z Z Z Measuring E Z Z Measuring E Z Z Measuring E Z Z Measuring E Z Measurin	nch/mm (Caxis (1 axis (detector unit) Measuring principle Resolution Sitylus tip Measuring force Radius of skid curvature Measuring method		800µm, 8 *Up to 2,400µm w Differentia Im (800µm range) / 0.001µm ( inch (32000µinch) / 0.04µinch 90°/5µm (200µinch) 4mN	178-583-01A 50mm 80µm, 8µm ith an optional stylus I inductance 80µm range) / 0.0001µm (8µm ra (3200µinch) / 0.004µinch (320µira 60°/2µm (80µinch)	178-583-02A (2inch)	
range Z  M R Detector S M R	A axis (detector unit)  Measuring principle  Resolution  Stylus tip  Measuring force Radius of skid curvature  Measuring method	0.01 <sub>1</sub> 0.4 <u>)</u> 60°/2µm (80µinch)	800µm, 8 *Up to 2,400µm w Differentia Im (800µm range) / 0.001µm ( inch (32000µinch) / 0.04µinch 90°/5µm (200µinch) 4mN	.bum, 8µm ith an optional stylus I inductance 80µm range) / 0.0001µm (8µm ra (3200µinch) / 0.004µinch (320µir		
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<u>N</u> R	Measuring force Radius of skid curvature Measuring method	60°/2µm (80µinch)	90°/5µm (200µinch) 4mN			
R	Radius of skid curvature Measuring method	0.75mN		ου / Ζμπι (ουμπισπ)	90°/5µm (200µinch)	
_	Measuring method			0.75mN	4mN	
			R40 mm (R1.57")			
		Skidded measurement / skidless measurement				
	Measuring speed	0.05 , 0.1 , 0.2 , 0.5 , 1.0mm/s (0.002 , 0.004 , 0.02 , 0.04 inch/s)				
	Orive speed	0.5, 1, 2, 5mm/s (0.02, 0.04, 0.08, 0.2 inch/s)				
	itraightness	0.3μm / 25mm (12μinch/ 1inch)		0.5μm / 50mm (20μinch/ 2inch)		
	leight adjustment	10mm (0.39inch)				
	ilt adjustment	±1.5°				
Standards		JIS1982 / JIS1994 / JIS2001 / ISO1997 / ANSI / VDA				
Parameters		Ra, Rq, Rz, Ry, Rp, Rv, Rt, R3z, Rsk, Rku, Rc, RPc, RSm, Rmax*¹, Rz1max*², S, HSC, RzIIS*³, Rppi, RΔa, RΔq, Rlr, Rmr, Rmr(c), Rσc, Rk, Rpk, Rvk, Mr1, Mr2, A1, A2, Vo, λa, λq, Lo, Rpm, tp*⁴, Htp*⁴, R, Rx, AR, W, AW, Wx, Wte, Possible Customize				
Measured profiles		Primary, Roughness, DF, Filtered waviness curve, R-Motif, W-Motif				
Graph analysis		BAC and ADC curves				
Data compensation		Parabola/ Hyperbola/ Ellipse/ Circle/ Conic/ Tilting, Compensation off				
Filter		2CR, PC75, Gaussian filter				
Cut-off length -	VC .	0.08, 0.25, 0.8, 2.5, 8.0mm				
$\frac{Cut-off leftgtff}{\lambda}$	LS *5	2.5, 8.0, 25mm (100, 320, 1000μinch)				
Sample length		0.08, 0.25, 0.8, 2.5, 8.0, 25.0mm				
Number of sampling	lengths	x1, x2, x3, x4, x5, x6, x7, x8, x9, x10, x11, x12, x13, x14, x15, x16, x17, x18, x19, x20				
Arbitrary length		0.1~25mm 0.1~50mm				
		Desired parameters can be selected for calculation and display				
	imple contour analysis function	Step, Step volume, Dimensions, Coordinate difference				
_	OAT function	Helps to adjust leveling during skidless measurement				
<u>R</u>	Real sampling function	Samples stylus displacement for a specified time without engaging detector traverse.				
	itatistical processing	Static measurement (max. 3 parameters) is possible. Static processing for MAX, MIN, AVERAGE, standard deviation, histogram and pass rate is possible				
_	GO/ NG judgement*6	Max rule / 16% rule / Average rule / Standard deviation (1 $\sigma$ , 2 $\sigma$ , 3 $\sigma$ )				
Functions S	itorage functions	10 measuring conditions can be stored in internal memory				
	rinting function	Measurement conditions / Calculation results / GO / NG judgement result / Calculation results for each sampling length / Measurement curve / BAC / ADC / Environmental setting information				
D	Display languages	Japanese, English, German, French, Italian, Spanish, Portuguese, Korean, Traditional Chinese, Simplified Chinese, Czech, Polish, Hungarian Turkish, Swedish, Dutch				
Sf	itorage	Internal memory: Measurement condition (10 sets)  Memory card (option): 500 measurement condition, 10000 measuring data, 10000 text data, 500 statistic data,  1 backup of machine setting, the last ten traces (Trace 10)				
F	external I/O	USB I/F, Digimatic output, RS-232C I/F, External SW I/F				
Rattery	anterrior y O	Two-way power supply: battery (rechargeable Ni-MH battery) and AC adapter				
	lattery	*Charging time: about 4 hours (may vary due to ambient temperature)				
Power supply	,	*Endurance: about 1500 measurements (differs slightly due to use conditions / environment)				
	ower consumption	50W				
	Display unit	275×198×109mm (10.8)				
(W^D^H) H	leight adjustment unit	130.9x63x99mm (5.16x2.48x3.90 inch)				
<u> </u>	Prive unit	128×35.8×46.6mm (5.04×1.41×1.83 inch) 154.5×35.8×46.6mm (6.08×1.41×1.83 inch)		(6.08×1.41×1.83inch)		
	Display unit			7kg		
	leight adjustment unit			4kg		
D	Drive unit	0.6			4kg	
Standard accessories		Detector* <sup>7</sup> , Stylus* <sup>8</sup> , Rough <b>270732</b> Printing paper <b>12BAL402</b> Touch-screen	ness specimen 12BAG834 protection sheet 12AAN04	Touch pen Strap for sty	Philips screwdriver, lus pen, Operation manual, nce manual, Warranty	

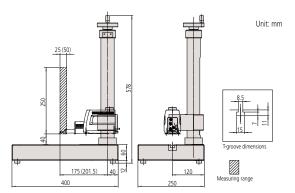
<sup>\*1:</sup> Only for VDA/ANSI/JIS'82 standards.
\*2: Only for JIS'97 standard.
\*3: Only for JIS'01 standard.
\*4: Only for ANSI standard.
\*5: \( \lambda \)s may not be switchable depending on standard selected.
\*6: Standard deviation only can be selected in ANSI.16% rule cannot be selected in VDA.
\*7: Either No.178-396-2 or No.178-397-2 is supplied as a standard accessory depending on the Order No. of the main unit for SJ-410 Series.

<sup>\*8:</sup> The standard stylus (No.12AAC731 or No.12AAB403), which is compatible with the detector supplied, is a standard accessory.

\*The dimensions in parentheses indicate those for SJ-412

Example of mounting on simple column stand. (Code No. 178-039)\*

\*For details see page 6.



\*The dimensions in parentheses indicate those for SJ-412



#### Whatever your challenges are, Mitutoyo supports you from start to finish.

Mitutoyo is not only a manufacturer of top-quality measuring products but one that also offers qualified support for the lifetime of the equipment, backed by comprehensive services that ensure your staff can make the very best use of the investment.

Apart from the basics of calibration and repair, Mitutoyo offers product and metrology training, as well as IT support for the sophisticated software used in modern measuring technology. We can also design, build, test and deliver measuring solutions and even, if deemed cost-effective, take your critical measurement challenges in-house on a sub-contract basis.



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#### **Mitutoyo America Corporation**

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